

**XI'AN IR-PERI
Company**

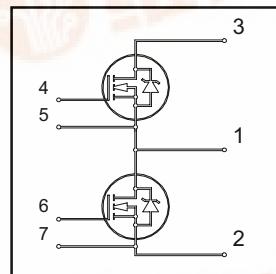
PRELIMINARY

FP150TA10U

“HALF-BRODGE” HEXFET Power MOSFET A - A - PAK

Features

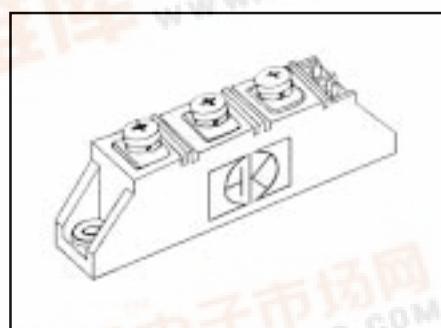
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175 °C Operating Temperature
- Fast Switching
- Fully Avalanche Rated



$V_{DSS}=100V$
 $R_{DS(on)}=0.009\Omega$
 $I_D=170A$

Benefits

- Increased operating efficiency
- Direct mounting to heatsink
- Performance optimized for power conversion: UPS, SMPS, Welding, Motor Control
- Lower EMI, requires less snubbing



Absolute Maximum Ratings

| | Parameter | Max. | Units |
|-------------------------|--|-------------|---------------|
| $I_D @ T_c=25^\circ C$ | Continuous Drain Current, $V_{GS}=10V$ | 170 | A |
| $I_D @ T_c=100^\circ C$ | Continuous Drain Current, $V_{GS}=10V$ | 120 | |
| I_{DM} | Pulsed Drain Current | 670 | |
| $P_D @ T_c=25^\circ C$ | Power Dissipation | 580 | W |
| | Linear Derating Factor | 3.8 | W/ $^\circ C$ |
| V_{GS} | Gate- to- Source Voltage | ± 30 | V |
| E_{AS} | Single Pulse Avalanche Energy | 1350 | mJ |
| I_{AR} | Avalanche Current | 100 | A |
| E_{AR} | Repetitive Avalanche Energy | 58 | mJ |
| dv/dt | Peak Diode Recovery dv/dt | 2.3 | V/ns |
| T_J | Operating Junction Temperature Range | -55 to +175 | $^\circ C$ |
| T_{STG} | Storage Temperature Range | -55 to +175 | |

Termal / Mechanical Characteristics

| | Parameter | Typ. | Max. | Units |
|-----------|---|------|------|--------------|
| R_{eJC} | Termal Resistance, Junction-to- Case- IBGT | - | 0.26 | $^\circ C/W$ |
| R_{eJC} | Termal Resistance, Junction-to- Case- Diode | - | 0.36 | |
| R_{eCS} | Termal Resistance, Csar-to- Sink- Module | 0.1 | - | N.m |
| | Mouting Torque, Case-to-Heatsink | - | 4.0 | |
| | Mouting Torque, Case-to-Terminal 1,2 & 3 | - | 3.0 | |
| | Weight of Module | 100 | - | g |

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Electrical Characteristics @ $T_J=25^\circ\text{C}$ (unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|-----------------------------------|--------------------------------------|------|-------|-------|---------------------|--|
| $V_{(\text{BR})\text{DSS}}$ | Drain-to-Source Breakdown Voltage | 100 | — | — | V | $V_{GS}=0\text{V}, I_D=250\mu\text{A}$ |
| $DV_{(\text{BR})\text{DSS}/DT_J}$ | Breakdown Voltage Temp. Coefficient | — | 0.11 | — | V/ $^\circ\text{C}$ | Reference to $25^\circ\text{C}, I_D=250\mu\text{A}$ |
| $R_{DS(\text{on})}$ | Static Drain-to-Source On-Resistance | — | — | 0.009 | Ω | $V_{GS}=10\text{V}, I_D=100\text{A}$ |
| $V_{GS(\text{th})}$ | Gate Threshold Voltage | 3.0 | — | 5.0 | V | $V_{DS}=10\text{V}, I_D=250\mu\text{A}$ |
| $g_{f\text{e}}$ | Forward Transconductance | 52 | — | — | S | $V_{DS}=50\text{V}, I_D=100\text{A}$ |
| $I_{DS\text{ss}}$ | Drain-to-Source Leakage Current | — | — | 25 | μA | $V_{DS}=100\text{V}, V_{GS}=0\text{V}$ |
| | | — | — | 250 | | $V_{DS}=80\text{V}, V_{GS}=0\text{V}, T_J=125^\circ\text{C}$ |
| $I_{GS\text{ss}}$ | Drain-to-Source Forward Current | — | — | 100 | nA | $V_{GS}=30\text{V}$ |
| | Drain-to-Source Reverse Current | — | — | -100 | | $V_{GS}=-30\text{V}$ |
| Q_g | Total Gate Charge | — | 260 | 390 | nC | $I_D=100\text{A}$ |
| Q_{gs} | Gate-to-Source Charge | — | 49 | 74 | | $V_{DS}=80\text{V}$ |
| Q_{gd} | Gate-to-Drain (Miller) Charge | — | 160 | 250 | | $V_{GS}=10\text{V}$ |
| $t_{d(on)}$ | Turn - On Delay Time | — | 24 | — | nS | $V_{DD} = 50\text{V}$ |
| t_r | Rise Time | — | 270 | — | | $I_D = 100\text{A}$ |
| $t_{d(off)}$ | Turn - Off Delay Time | — | 45 | — | | $R_G = 1.03\Omega$ |
| t_f | Fall Time | — | 140 | — | | $V_{GS} = 10\text{V}$ |
| L_D | Internal Drain Inductance | — | 5.0 | — | nH | Between lead,6mm from package and center of die |
| L_S | Internal Source Inductance | — | 13 | — | | |
| C_{iss} | Input Capacitance | — | 6790 | — | pF | $V_{GS} = 0\text{V}$ |
| C_{oss} | Output Capacitance | — | 2470 | — | | $V_{DS} = 25\text{V}$ |
| C_{rss} | Reverse Transfer Capacitance | — | 990 | — | | $f=1.0\text{MHz}$ |
| C_{oss} | Output Capacitance | — | 10740 | — | | $V_{GS}=0\text{V}, V_{DS}=1.0\text{V}, f=1.0\text{MHz}$ |
| C_{oss} | Output Capacitance | — | 1180 | — | | $V_{GS}=0\text{V}, V_{DS}=80\text{V}, f=1.0\text{MHz}$ |
| $C_{oss\text{ eff.}}$ | Effective Output Capacitance | — | 2210 | — | | $V_{GS}=0\text{V}, V_{DS}=0\text{V} \text{ to } 80\text{V}$ |

Dynamic Characteristics - $T_J=125^\circ\text{C}$ (unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Conditions |
|----------|---|---|------|------|-------|---|
| I_S | Continuous Source Current (Body Diode) | — | — | 174 | A | MOSFET symbol showing the integral reverse p-n junction diode |
| I_{SM} | Pulsed Source Current (Body Diode) | — | — | 670 | | |
| V_{SD} | Diode Forward Voltage | — | — | 1.3 | V | $T_J=25^\circ\text{C}, I_S=100\text{A}, V_{GS}=0\text{V}$ |
| t_{rr} | Diode Reverse Recovery Time | — | 220 | 330 | nS | $T_J=25^\circ\text{C}, I_F=100\text{A}$ |
| Q_{rr} | Diode Reverse Recovery Charge | — | 1640 | 2460 | nC | $dI/dt=100\text{A}/\mu\text{s}$ |
| t_{on} | Forward Turn-On Time | Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D) | | | | |